FAIRCHILD

SEMICONDUCTOR

FDS6675BZ P-Channel PowerTrench[®] MOSFET -30V, -11A, 13mΩ

General Description

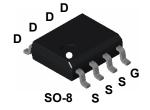
This P-Channel MOSFET is producted using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance.

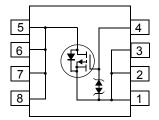
This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)}$ = 13m Ω at V_{GS} = -10V, I_D = -11A
- Max r_{DS(on)} = 21.8mΩ at V_{GS} = -4.5V, I_D = -9A
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 5.4 KV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handing capability
- RoHS Compliant





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		-30	V
V _{GS}	Gate to Source Voltage		±25	V
	Drain Current -Continuous	(Note 1a)	-11	^
D	-Pulsed		-55	— A
	Power Dissipation for Single Operation	(Note 1a)	2.5	
P _D		(Note 1b)	1.2	W
		(Note 1c)	1.0	
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note 1a)	50	°C/W
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case (Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS6675BZ	FDS6675BZ	13"	12mm	2500 units

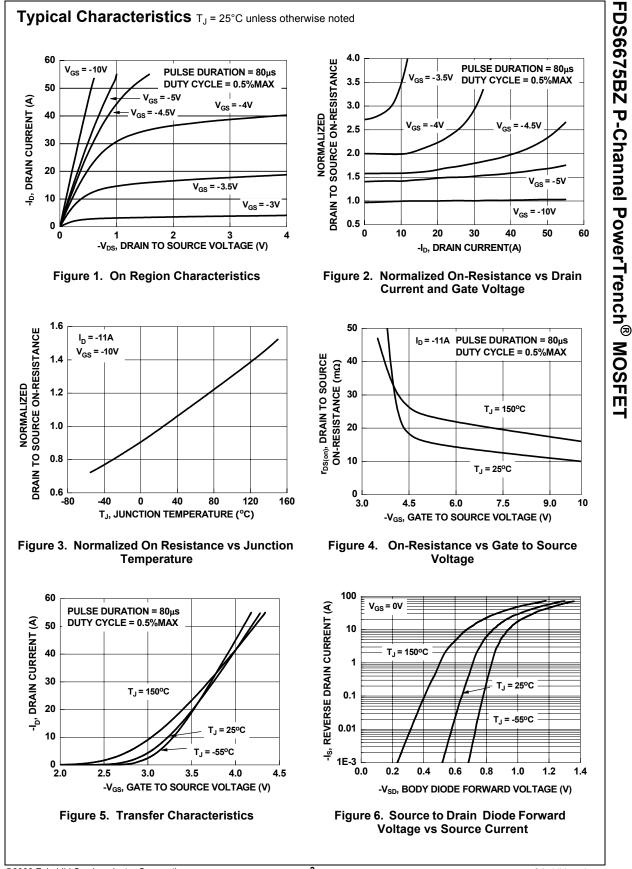
March 2009

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emperature Coefficient	25°C V _{GS} = -10V , I _D = -11A		15.7		
	V _{GS} = -10V , I _D = -11A		10.7		mV/°C
ain to Source On Resistance					IIIV/ C
ain to Source On Resistance			10.8	13.0	-
	V _{GS} = -4.5V, I _D = -9A		17.4	21.8	mΩ
	V _{GS} = -10V, I _D = -11A T _J = 125°C		15.0	18.8	
orward Transconductance	$V_{DS} = -5V, I_D = -11A$		34		S
			1955	2470	pF
	V _{DS} = -15V, V _{GS} = 0V,				pF
	f = 1MHz				pr
Irn-On Delay Time	V _{DD} = -15V, I _D = -11A		3.0	10	ns ns
	$-V_{GS} = -10V, R_{GS} = 6\Omega$				ns
	-				ns
	V _{DS} = -15V, V _{GS} = -10V, I _D = -11A		44	62	nC
	0		25	35	nC
tal Gate Charge				55	
tal Gate Charge ate to Source Gate Charge	V _{DS} = -15V, V _{GS} = -5V,		7.2	- 55	nC
atal Gate Charge ate to Source Gate Charge ate to Drain Charge	− V _{DS} = -15V, V _{GS} = -5V, I _D = -11A		-		-
ate to Source Gate Charge ate to Drain Charge			7.2		nC
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics	I _D = -11A		7.2 11.4		nC nC
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics purce to Drain Diode Forward Voltage	$I_D = -11A$ $V_{GS} = 0V, I_S = -2.1A$		7.2	-1.2	nC nC V
ate to Source Gate Charge ate to Drain Charge e Diode Characteristics	I _D = -11A		7.2 11.4		nC nC
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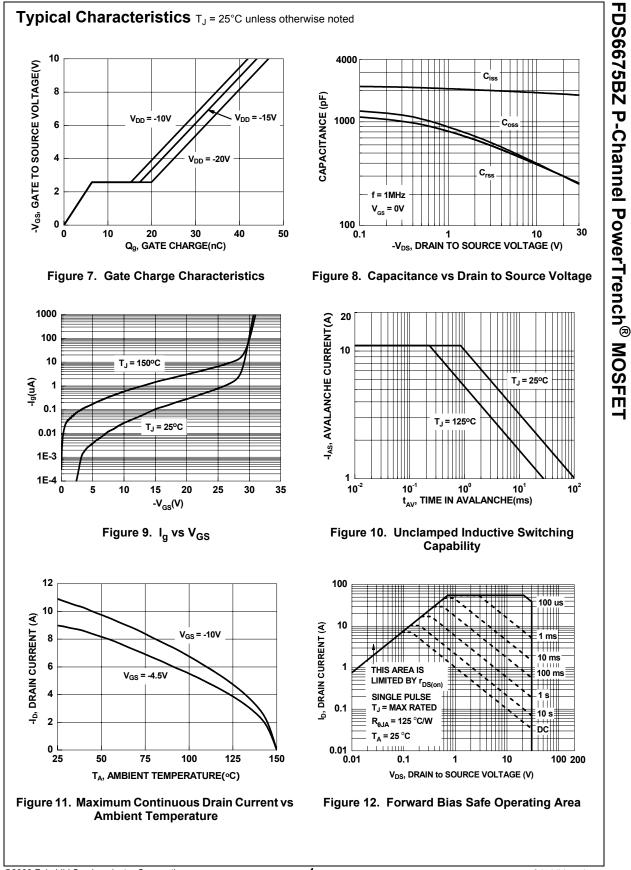
FDS6675BZ P-Channel PowerTrench[®] MOSFET

Scale 1 : 1 on letter size paper

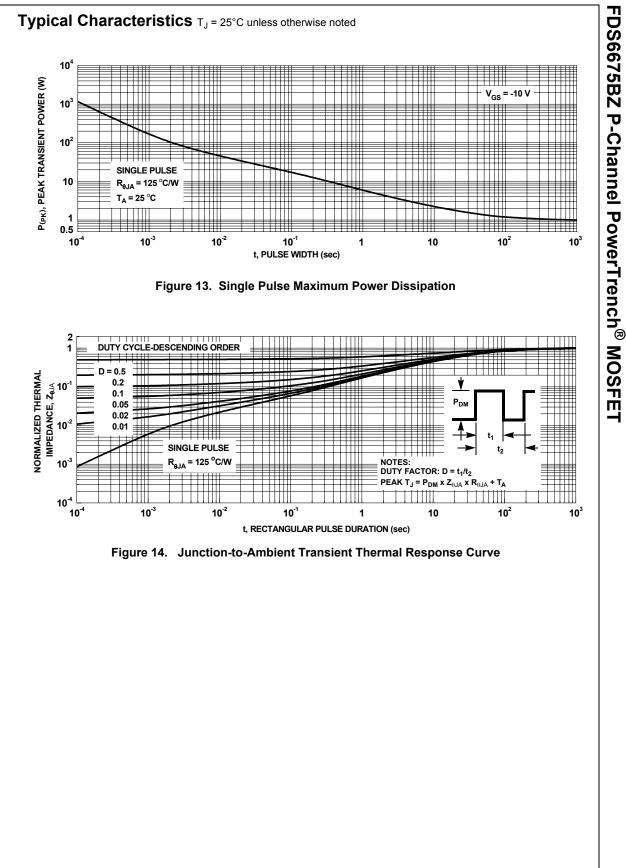
Pulse Test:Pulse Width <300 us, Duty Cycle < 2.0%
 The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



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